

# Silicon, SPDT Switch, Reflective, 24 GHz to 32 GHz

#### <span id="page-0-0"></span>**FEATURES**

**Reflective design Low insertion loss: 1.1 dB High isolation: 38 dB High input linearity P0.1dB: 37 dBm IP3: 65 dBm High RF input power handling 28 dBm average 36 dBm peak 3.3 V single-supply operation Internal negative voltage generator RF settling time (0.1 dB final RF output): 70 ns [20-terminal, 3 mm × 3 mm, RoHS-compliant, land grid array](#page-10-0)  [package](#page-10-0)**

#### <span id="page-0-1"></span>**APPLICATIONS**

**Industrial scanner Test instrumentation Cellular infrastructure: 5G millimeter wave Military radios, radars, electronic counter measures (ECMs) Microwave radios and very small aperture terminals (VSATs)**

#### <span id="page-0-3"></span>**GENERAL DESCRIPTION**

The ADRF5300 is a reflective, SPDT switch manufactured in the silicon process.

The ADRF5300 is developed for 5G applications ranging from 24 GHz to 32 GHz. The ADRF5300 has a low insertion loss of 1.1 dB, a high isolation of 38 dB, and an RF input power handling capability of 28 dBm average and 36 dBm peak.

Data Sheet **[ADRF5300](https://www.analog.com/ADRF5300?doc=ADRF5300.pdf)** 

#### <span id="page-0-2"></span>**FUNCTIONAL BLOCK DIAGRAM**



The ADRF5300 incorporates a negative voltage generator (NVG) to operate with a single positive supply of 3.3 V ( $V_{DD}$ ) applied to the VDD pin. The device employs CMOS- and low voltage transistor to transistor logic (LVTTL)-compatible controls.

The ADRF5300 is packaged in a 20-terminal,  $3 \text{ mm} \times 3 \text{ mm}$ , [RoHS-compliant, land grid array \(LGA\) package](#page-10-0) and can operate from −40°C to +105°C.

#### **Rev. 0 [Document Feedback](https://form.analog.com/Form_Pages/feedback/documentfeedback.aspx?doc=ADRF5300.pdf&product=ADRF5300&rev=0)**

**Information furnished by Analog Devices is believed to be accurate and reliable. However, no responsibility is assumed by Analog Devices for its use, nor for any infringements of patents or other rights of third parties that may result from its use. Specifications subject to change without notice. No license is granted by implication or otherwise under any patent or patent rights of Analog Devices. Trademarks and registered trademarks are the property of their respective owners.**

**One Technology Way, P.O. Box 9106, Norwood, MA 02062-9106, U.S.A. Tel: 781.329.4700 ©2020 Analog Devices, Inc. All rights reserved. [Technical Support](http://www.analog.com/en/content/technical_support_page/fca.html) [www.analog.com](http://www.analog.com/)** 

# **TABLE OF CONTENTS**



### Input Power Compression and Third-Order Intercept ..........7

### <span id="page-1-0"></span>**REVISION HISTORY**

9/2020-Revision 0: Initial Version

### <span id="page-2-0"></span>**SPECIFICATIONS**

 $V_{\text{DD}} = 3.3$  V, control voltage (V $_{\text{CTRL}}$ ) = 0 V or V<sub>DD</sub>, T<sub>CASE</sub> = 25°C, and a 50  $\Omega$  system, unless otherwise noted.

#### <span id="page-2-2"></span>**Table 1.**



<sup>1</sup> Performance is limited by the test setup.

<sup>2</sup> For 105°C operation, the power handling degrades from the T<sub>CASE</sub> = 85°C specification by 3 dB.

### <span id="page-2-1"></span>**TIMING SPECIFICATIONS**

Se[e Figure 14](#page-7-4) for the timing diagram.

#### <span id="page-2-3"></span>**Table 2.**



 $1$  A maximum of 10 dBm RF input power can be applied during the t<sub>POWERUP</sub> wait time.

### <span id="page-3-0"></span>ABSOLUTE MAXIMUM RATINGS

For the recommended operating conditions, se[e Table 1.](#page-2-2) 

#### **Table 3.**



Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

#### <span id="page-3-1"></span>**THERMAL RESISTANCE**

Thermal performance is linked directly to printed circuit board (PCB) design and operating environment. Careful attention to PCB thermal design is required.

 $\theta$ <sub>JC</sub> is the junction to case bottom (channel to package bottom) thermal resistance.

#### **Table 4. Thermal Resistance**



#### <span id="page-3-2"></span>**ELECTROSTATIC DISCHARGE (ESD) RATINGS**

The following ESD information is provided for handling of ESD-sensitive devices in an ESD protected area only.

Human body model (HBM) per ANSI/ESDA/JEDEC JS-001.

Field induced charged device model (FICDM) per ANSI/ESDA/ JEDEC JS-002.

#### **ESD Ratings for ADRF5300**

#### **Table 5. ADRF5300, 20-Terminal LGA**



#### <span id="page-3-3"></span>**ESD CAUTION**



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

# <span id="page-4-0"></span>PIN CONFIGURATION AND FUNCTION DESCRIPTIONS



Figure 2. Pin Configuration (Top View)

#### **Table 6. Pin Function Descriptions**



#### <span id="page-4-1"></span>**INTERFACE SCHEMATICS**



<span id="page-4-2"></span>Figure 3. RFC, RF1, and RF2 Pins Interface Schematic



<span id="page-4-4"></span>Figure 4. CTRL Pin Interface Schematic



<span id="page-4-3"></span>Figure 5. VDD Pin Interface Schematic

# <span id="page-5-0"></span>TYPICAL PERFORMANCE CHARACTERISTICS

### <span id="page-5-1"></span>**INSERTION LOSS, RETURN LOSS, AND ISOLATION**

 $V_{DD}$  = 3.3 V,  $V_{CTRL}$  = 0 V or  $V_{DD}$ ,  $T_{CASE}$  = 25°C, and a 50  $\Omega$  system, unless otherwise noted. Measured on the probe matrix board using ground signal ground (GSG) probes close to the RFC, RF1, and RF2 pins.







Figure 9. Return Loss vs. Frequency

#### <span id="page-6-0"></span>**INPUT POWER COMPRESSION AND THIRD-ORDER INTERCEPT**

 $V_{DD} = 3.3$  V,  $V_{CTRL} = 0$  V or  $V_{DD}$ ,  $T_{CASE} = 25^{\circ}$ C, and a 50  $\Omega$  system, unless otherwise noted. All of the large signal performance parameters are measured on the [ADRF5300-EVALZ.](https://www.analog.com/eval-ADRF5300?doc=ADRF5300.pdf)



Figure 11. Input IP3 vs. Frequency, RF1 Selected



Figure 13. Input IP3 vs. Frequency, RF2 Selected

### <span id="page-7-0"></span>THEORY OF OPERATION

The ADRF5300 incorporates a driver to perform logic functions internally and to provide the user with the advantage of a simplified positive voltage control interface. The driver features a single digital control input pin (CTRL) that controls the state of the RF paths. The logic level applied to the CTRL pin determines which RF port is in the insertion loss state and which port is in the isolation state (see [Table 7\)](#page-7-5).

#### <span id="page-7-1"></span>**RF INPUT AND OUTPUT**

All of the RF ports (RFC, RF1, and RF2) are dc-coupled to 0 V. When the RF line potential is equal to 0 V, no dc blocking capacitor is required at the RF ports.

The RF ports are internally matched to 50  $\Omega$ . Therefore, external matching networks are not required.

The ADRF5300 is bidirectional with equal power handling capabilities. An RF input signal ( $RF_{IN}$ ) can be applied to the RFC port, RF1 port, or RF2 port.

The insertion loss path conducts the RF signal between the selected RF throw port and the RF common port. The isolation path provides high loss between the insertion loss path and the unselected, reflective RF throw port.

#### <span id="page-7-2"></span>**POWER SUPPLY**

The ADRF5300 operates on a positive single supply and includes an NVG with ultralow spurious performance. Bypassing capacitors are recommended on the supply lines to filter high frequency noise.

The power-up sequence is as follows:

- 1. Connect GND to ground.
- 2. Power up the supply input, VDD.
- 3. Apply the digital control input, CTRL. Applying CTRL before applying the VDD supply inadvertently forward biases and damages the internal ESD protection structures. To avoid this damage, use a series  $1 \text{ k}\Omega$  resistor to limit the current flowing into the CTRL pin. Pull the CTRL pin to VDD or GND using a resistor if the controller output is in a high impedance state after VDD is powered up and the CTRL pin is not driven to a valid logic state.
- 4. Apply the RF input signal.

The power-down sequence is the reverse order of the power-up sequence.

#### <span id="page-7-3"></span>**TIMING REQUIREMENTS**

There are timing requirements for the proper operation of the bias and control circuits. Se[e Table 2 f](#page-2-3)or the timing specifications. Se[e Figure 14](#page-7-4) for the timing requirements.

After VDD reaches the operating range, tPOWERUP defines the wait time before the recommended maximum RF power can be applied. During this time, a maximum of 10 dBm RF input power can be applied.

The minimum wait time before switching states is defined by  $t_{HOLD}$ .

The maximum rise and fall time of the CTRL pulse is defined by t<sub>SLEW</sub>.



Figure 14. Timing Requirements

#### <span id="page-7-5"></span><span id="page-7-4"></span>**Table 7. Control Voltage Truth Table**



### <span id="page-8-0"></span>APPLICATIONS INFORMATION **LAYOUT CONSIDERATIONS**

<span id="page-8-1"></span>The design of the [ADRF5300-EVALZ](https://www.analog.com/eval-ADRF5300?doc=ADRF5300.pdf) serves as a layout recommendation for the ADRF5300 application.

The ADRF5300-EVALZ is a 4-layer evaluation board. The outer copper (Cu) layers are 0.5 oz (0.7 mil) plated to 1.5 oz (2.2 mil) separated by dielectric materials[. Figure 15](#page-8-4) shows the ADRF5300-EVALZ stack up.

For additional information on application circuit design, see the ADRF5300-EVALZ user guide.



Figure 15. ADRF5300-EVALZ Stack Up

<span id="page-8-4"></span>All RF and dc traces are routed on the top copper layer, whereas the inner and bottom layers are grounded planes that provide a solid ground for the RF transmission lines. The top dielectric material is 8 mil Rogers RO4003, offering optimal high frequency performance. The middle and bottom dielectric materials provide mechanical strength. The total board thickness is 62 mil, which allows 2.4 mm RF launchers to connect at the board edges.

### <span id="page-8-2"></span>**RF AND DIGITAL CONTROLS**

The RF transmission lines are designed using a coplanar waveguide (CPWG) model, with a trace width of 14 mil and a ground clearance of 7 mil to have a characteristic impedance of 50  $Ω$ . For optimal RF and thermal grounding, as many plated through vias as possible are arranged around transmission lines and under the exposed pad of the package.

The RF ports (RFC, RF1, and RF2) connect through 50  $\Omega$ transmission lines to the 2.4 mm RF launchers. On the VDD pin, a 100 pF bypass capacitor filters high frequency noise.

[Figure](#page-8-5) 16 shows the simplified application circuit for the ADRF5300-EVALZ.



### <span id="page-8-5"></span><span id="page-8-3"></span>**PROBE MATRIX BOARD**

The probe matrix board is a 4-layer evaluation board. This board also uses an 8 mil Rogers RO4003 dielectric. The outer copper (Cu) layers are 0.5 oz (0.7 mil) plated to 1.5 oz (2.2 mil). The RF transmission lines were designed using a CPWG model with a width of 14 mil and a ground spacing of 7 mil to have a characteristic impedance of 50  $\Omega$ .



Figure 17. Probe Matrix Board Stack Up

<span id="page-8-6"></span>[Figure 17](#page-8-6) shows the probe matrix board stack up, which is the same as the ADRF5300-EVALZ, but with a different layout that is designed to perform measurements using GSG probes at close proximity to the RFC, RF1, and RF2 pins. Probing reduces the reflections caused by mismatch arising from the connectors, cables, and board layout, which results in a more accurate measurement of the insertion loss and the return loss. Signal coupling between the RF probes limits the isolation measurement[. Figure 18](#page-9-0) shows the top view of the probe matrix board layout.

# additional and the contract of the contract of

<span id="page-9-0"></span>

The probe matrix board includes a through reflect line (TRL) calibration kit allowing board loss de-embedding. The actual board duplicates the same layout in matrix form, which allows multiple devices to assemble at once. Insertion loss and return loss measurements are made on the probe matrix board, whereas isolation measurements are made on the [ADRF5300-EVALZ.](https://www.analog.com/eval-ADRF5300?doc=ADRF5300.pdf) 

# <span id="page-10-0"></span>OUTLINE DIMENSIONS



Figure 19. 20-Terminal Land Grid Array [LGA] 3 mm × 3 mm Body and 0.75 mm Package Height (CC-20-9) Dimensions shown in millimeters

#### <span id="page-10-1"></span>**ORDERING GUIDE**



 $1 Z =$  RoHS Compliant Part.

**©2020 Analog Devices, Inc. All rights reserved. Trademarks and registered trademarks are the property of their respective owners. D20780-9/20(0)** 



www.analog.com

**04-13-2020-A**

Rev. 0 | Page 11 of 11